

APPLICATION NO.  
09/720,084

APPLICANT  
EBBESEN, et al.

(Use several sheets if necessary)

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GROUP	2613
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## U.S. PATENT DOCUMENTS

[illegible]

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER							DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION	
												YES	NO
↓	DE31	1	6	3	4	8	A1	9-9-1982	Germany	—	—	X*	
	JP0	5	2	9	9	5	33	11-12-1993	Japan	↓	↓	X*	
	WO96	3	8	0	2	5	A1	11-28-96	WIPO	↓	↓	X	
	WO98	5	8	3	8	3		12-23-98	WIPO	↓	↓	X	
										↓	↓		

## OTHER DOCUMENTS

**OTHER DOCUMENTS** (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.

JH	G. HOROWITZ, "Organic Field-Effect Transistors" Advanced Materials, Vol. 10, pp. 365-377; (1998)
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EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.